

**Amendments to the Claims:**

This listing of claims replaces all prior versions, and listings, of claims in this application.

**Listing of Claims:**

1. (Previously amended) A method for testing a plurality of driver circuits on an array glass of an active matrix organic light emitting display (AMOLED) before organic light emitting diodes are implanted, each of the driver circuits including: a scan line, a data line, a power line, a first transistor, a second transistor and a first capacitor; the method comprising the steps of:
  - (a) repeating the steps (b) ~ (e) until a first signal and a second signal outputted from each of the driver circuits are retrieved;
  - (b) enabling one of the driver circuits via the scan line;
  - (c) charging the first capacitor and retrieving the first signal from the data line when the first capacitor is discharged via the first transistor;
  - (d) disposing a conductive board above the array glass to form a second capacitor between the conductive board and the array glass;
  - (e) charging the second capacitor and retrieving the second signal from the power line when the second capacitor is discharged via the second transistor; and
  - (f) analyzing the first and second signals to determine the functionality of said one of the driver circuits.
2. (Original) The method of claim 1, wherein the step (c) further comprises:
  - (g) providing a high level voltage onto the data line to charge the first capacitor via the first transistor;

- (h) providing a low level voltage onto the data line to discharge the first capacitor  
  
via the first transistor; and
  - (i) retrieving the first signal from the data line while the first capacitor is discharged.
3. (Original) The method of claim 1, wherein the step (e) further comprises:
- (j) providing a high level voltage onto the power line to charge the second capacitor  
  
via the second transistor;
  - (k) providing a low level voltage onto the power line to discharge the second  
  
capacitor via the second transistor; and
  - (l) retrieving the second signal from the power line while the second capacitor is  
  
discharged.
4. (Original) The method of claim 1, wherein the first and second signals are a  
  
charge signal, a voltage signal or a current signal.
5. (Previously amended) The method of claim 1, wherein the step (f) further  
comprises:
- (m) respectively computing an average value of the first signals and an average  
  
value of the second signals of the driver circuits;

(n) determining whether the value of the first signal of each of the driver circuits is

within  $\pm 75\%$  of the average value of the first signals; and

(o) determining whether the value of the second signal of each of the driver circuits

is within  $\pm 75\%$  of the average value of the second signals;

wherein, if the value of the first signal of the driver circuit is within

$\pm 75\%$  of the average value of the first signals, the first transistor and the first

capacitor of said one of the driver circuits has normal functionality, and if the

value of the second signal of the driver circuit is within  $\pm 75\%$  of the average

value of the second signals, the second transistor of said one of the driver

circuits has normal functionality.

6. (Withdrawn) A apparatus for testing a plurality of driver circuits of an active matrix organic light emitting display (AMOLED) before organic light emitting diodes are implanted, the apparatus comprising:

a pixel selection device for selecting one of the driver circuits;

a signal extractor for retrieving a signal; and

a signal analyzer, connected to the signal extractor, for storing and analyzing

the signal to determine the functionality of said one of the driver circuits.